

NFC Testing

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E-Smart 2008, Sophia Antipolis

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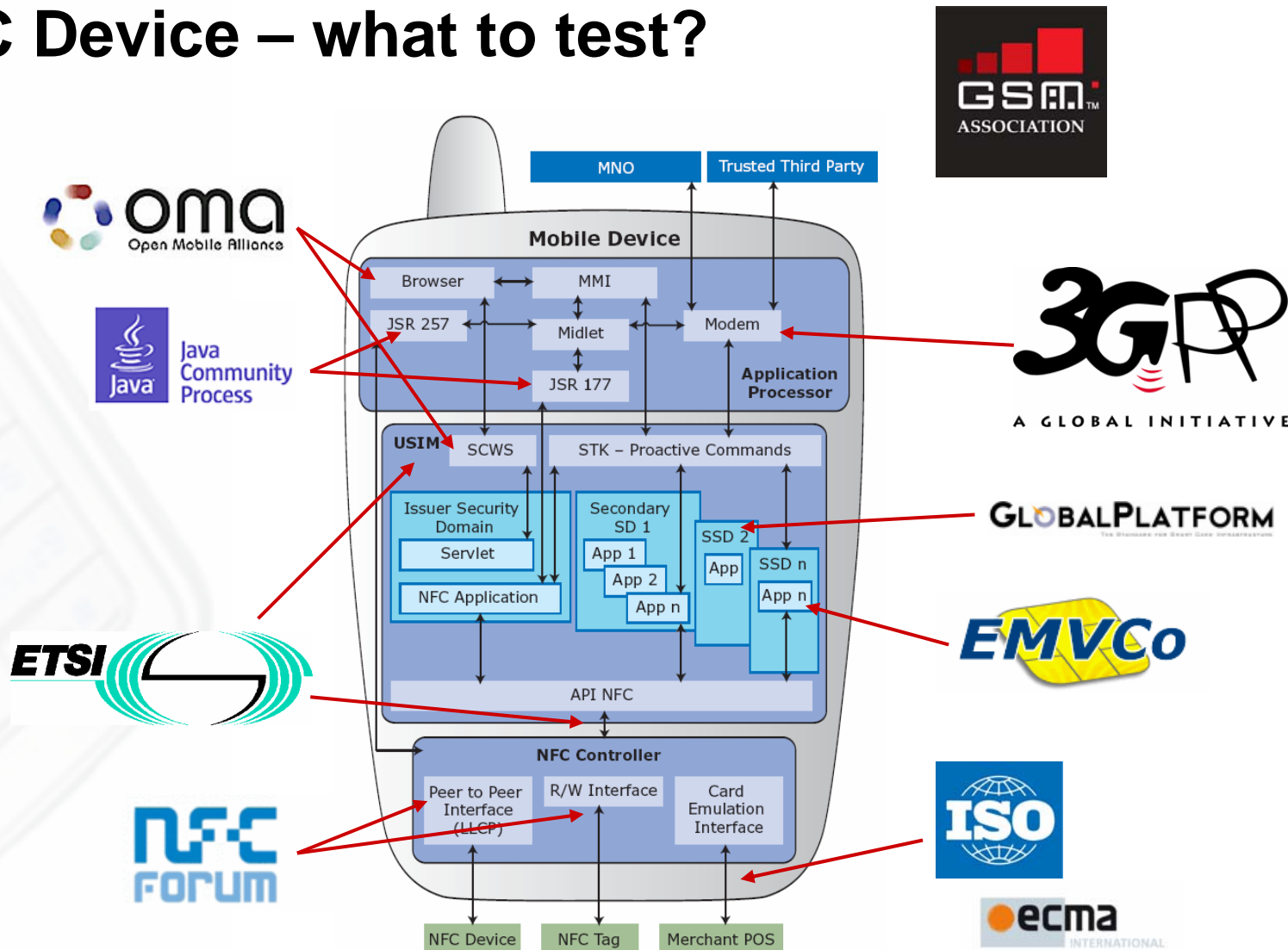
- Research Topics
 - Software: Contactless Applications and Infrastructure
 - Hardware: Testing & Interoperability
 - Security
 - Usability

- Founded by Industry Partners
 - Mobilkom Austria (Vodafone Partner)
 - NXP Semiconductors
 - Omnikey/Assa Abloy (HID Global)

- NFC Forum Member



NFC Device – what to test?



NFC Testing Working Group



- Testing Working Group @NFC Forum
 - Test Case for P2P, R/W Mode and Card Emulation
 - System Testing (SWP, HCI, Integration, NDEF, ...)
 - Digital Testing Protocol (Contactless)
 - Secure Element NOT PART of NFC Testing
 - Plug-Fest Testing
 - 1. Plugfest Dez. 2007 (Athens)
 - 2. Plugfest Nov. 2008 (Monaco)
 - Physical Testing

NFC Compliance Working Group



- Specification of Test Equipment
 - Request for Information (handed out already)
 - Definition of the Requirements
 - MicroPros, Comprion, AT4Wireless ...

- Specification of Test Houses
 - Request for Information
 - Definition of the Requirements
 - Virtual, ETSI, ...

- Invitation for Presentation



NFC Testing - Overview

- Physical characteristics of electromagnetic field (EM field)
 - Amplitude
 - Power of generated EM field
- Interaction with other devices
 - Detect other devices (“Polling Loop”, “Mode Switch”)
 - Exchange data
 - Anti-collision
 - Communication at different data rates
- Requirements for Test System
 - Test system must be able to control device under test
 - Test system must be able to move device under test
 - Measurements (Amplitude, Power) must be taken



Test System: Challenges

- Mobile phones
 - Location of Antenna different
 - Vary in size and form
 - Most NFC phones still prototypes
 - J2ME Clients on phones using different APIs
 - Also different for eg. SD Cards/USB Readers
- Mobile phones use different methods to connect than readers
 - Bluetooth
 - TCP/IP (GPRS, WLAN)
- Test software (on Device) must be adopted for each new device.

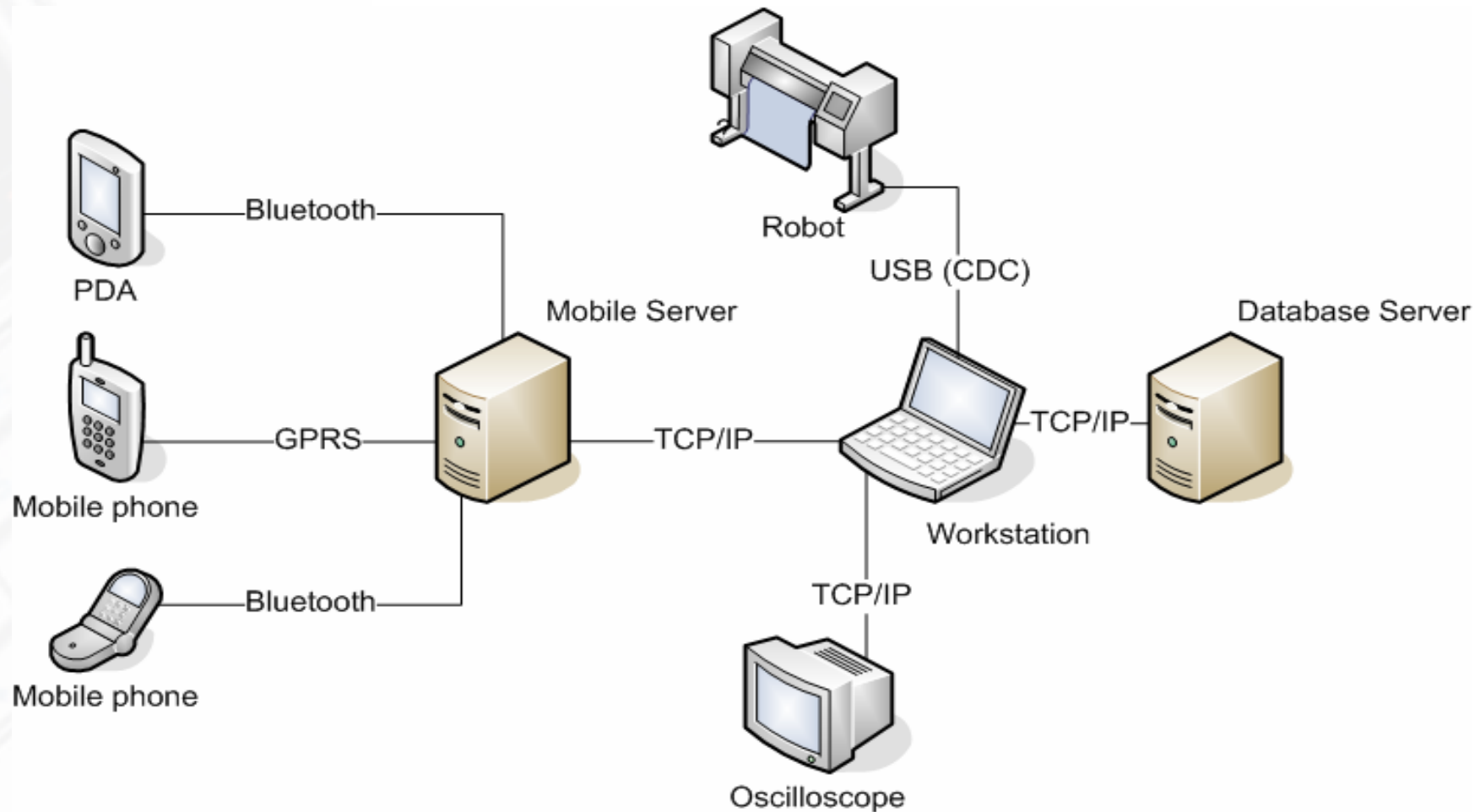
NFC Forum Test System: Requirements

- Control Device under test (DUT)
 - NFC Initiator (Active)
- Target
 - NFC Forum Tag Type 1/2/3/4 (Passiv)
 - NFC Peer-to-Peer device (Passiv and Active)
- Robot to move device under test
 - One direction only
 - Different windows and resolutions

NFC Forum Test System: Tests

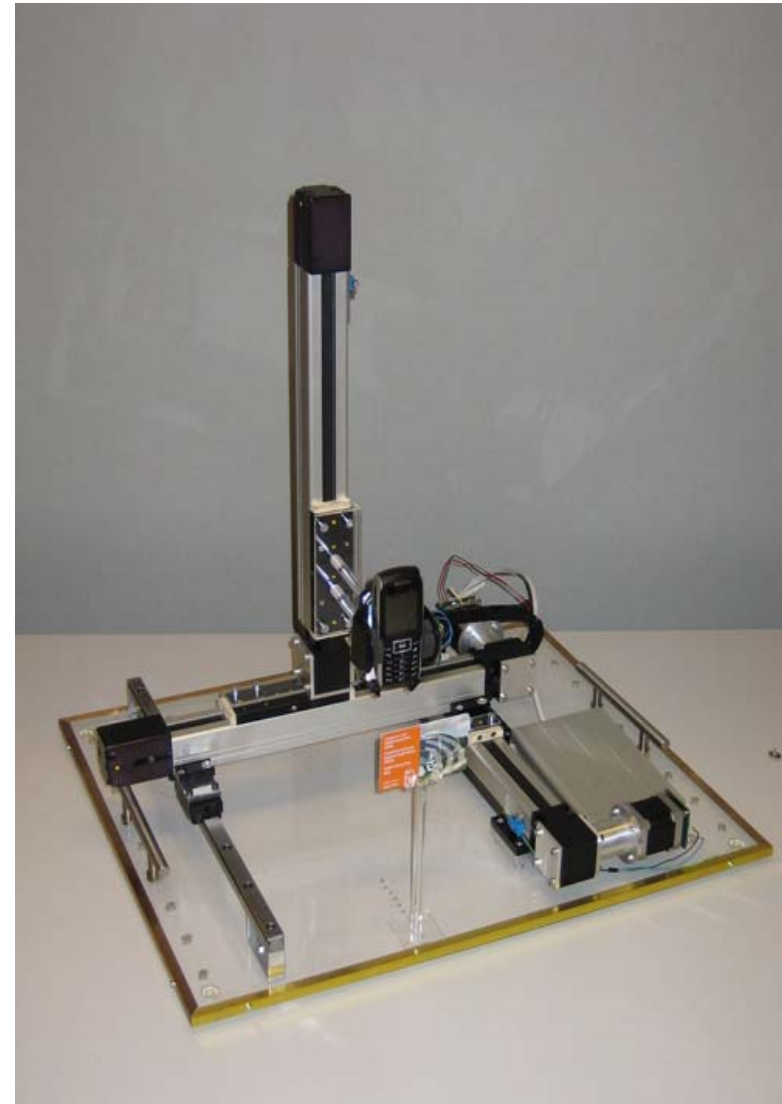
- Range tests
 - How far can a device detect other devices?
- Anti collision
 - Is a device able to detect a specific targets?
 - Is a device able to enumerate all available targets?
- Window tests
 - Is a device able to detect a target in a specific window?
 - Range varies between 0 mm (in touch) and 100 mm

HF-Hagenberg Test System: Overview



Robot

- 3 Axis
- 0.25 mm resolution each
- 20 cm range each
- Mobile phone holder
- 10 cm distance of DUT to metal
- Connected via USB
- Supports ISO14443 A, B & F
- Swiping Card Simulation (*Wachler*)



Software suite

- Task
 - Scripting of Task Cased (Python)
 - Control of DUT thru device abstraction Layer
 - Control Tests while running
 - Connection pooling of DUTs (e. g. P2P or emulated Felica)
 - Robot control
- Results
 - 3D Logs + viewer
 - Log Files creation
- Test configuration
- Easy integration of new test scripts

Software Suite – Device Abstraction Layer

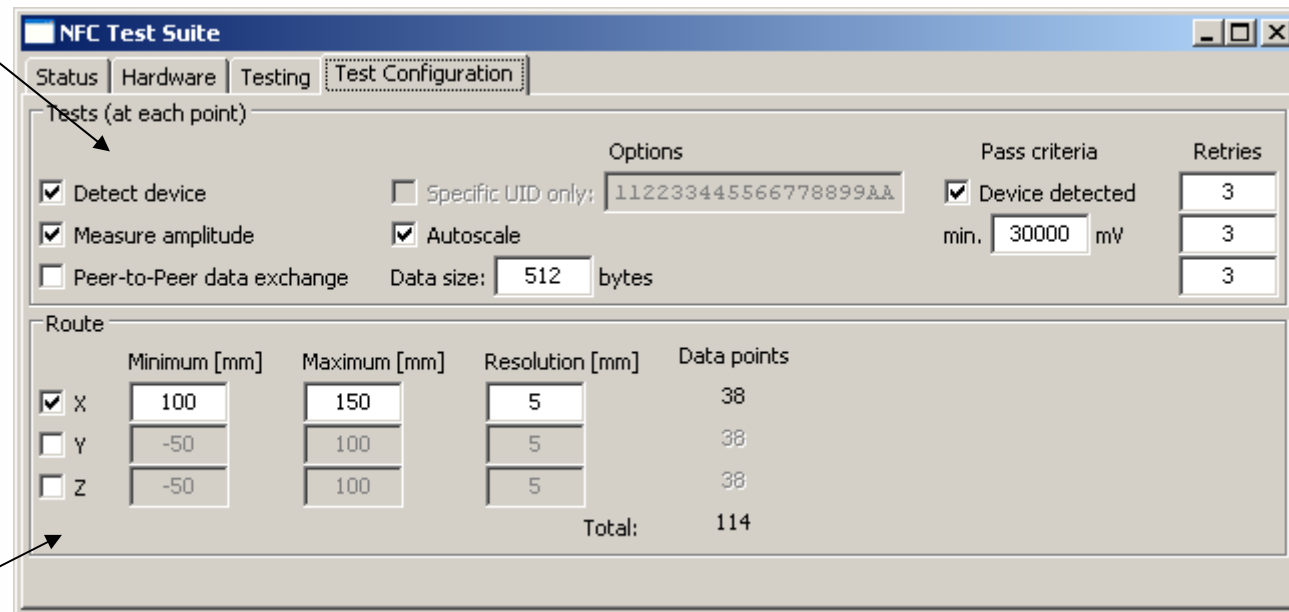
- Server for each connection method
- All servers are controlled via a single interface
 - Provide list of connected devices
 - 'Produce' devices which can be accessed in tests
- All devices share a common interface
 - Provides enumeration of capabilities
 - Defines how data is exchanged
- Test scripts access all devices the same way

How a test works

- Take measurements in a cube of given dimensions
- Steps to take:
 - Connect robot and oscilloscope
 - Connect device under test
 - Place device under test in robot
 - Place target and oscilloscope antenna
 - Configure test in software suite
 - Select DUT, test configuration and target in software suite
 - Run test
 - Admire 3D log view

Screenshots: Test configuration

- Available tests that will be executed at each point



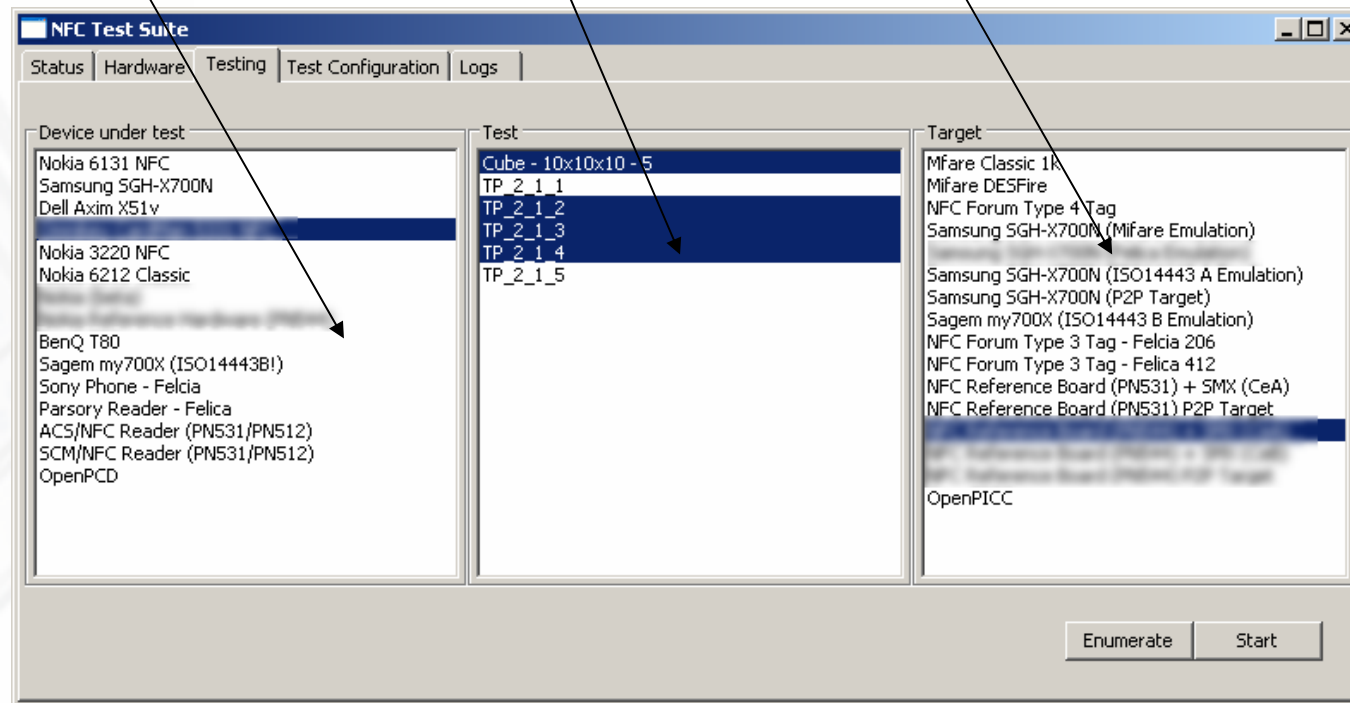
- Area where tests take place

Screenshots: Test selection

DUT

Test

Target



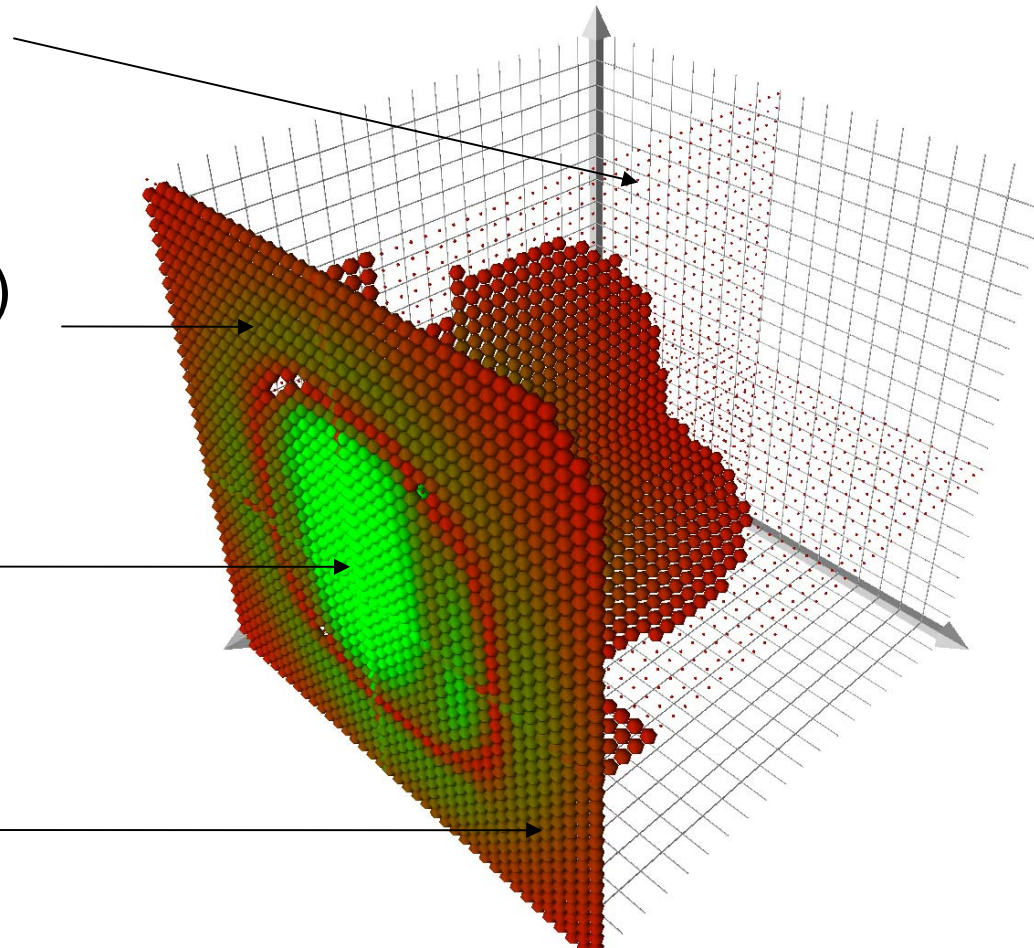
Screenshots: 3D log view

No amplitude measured

Front plain (Y and Z axis)

High amplitude

Low amplitude



Further „NFC“ Testing

- Digital Protocols
 - Contactless Interface
 - SWP Interface
 - Combined Testing
- Performance
- Applications
 - JSR, SCWS
- Systems



Conclusion

- RF/NDEF Testing: basic functionality of an NFC Device
- Testing of whole system complex
 - JSR Testing (Java APIs)
 - SWP Testing
 - UICC Testing
 - Application/Unit Tests
 - Not only functionally tests, but also performance tests



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congress.nfc-research.at



Happy to answer any questions

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<http://www.nfc-research.at>